Dual Channel USB3.0 Redriver/Equalizer

Check for Samples: SN65LVPE502

FEATURES

- **Single Lane USB 3.0 Equalizer/Redriver**
- **Selectable Equalization, De-emphasis and Output Swing Control**
- **Integrated Termination**
- **Hot-Plug Capable**
- **Receiver Detect**
- **Low Power:**
  - **315mW(TYP), V_{CC} = 3.3V**
- **Auto Low Power Modes:**
  - **5mW (TYP) When no Connection Detected**
  - **70mW (TYP) When in U2/U3 Mode**
- **Excellent Jitter and Loss Compensation Capability: to 24"**
  - **24" of 6 mil Stripline on FR4**
  - **12" on Input and 4m, 26AWG USB 3.0 Cable on Output**
- **Small foot print – 24 Pin (4mm × 4mm) QFN Package**
- **High Protection Against ESD Transient**
  - **HBM: 5,000 V**
  - **CDM: 1,500 V**
  - **MM: 200 V**

APPLICATIONS

- **Notebooks, Desktops, Docking Stations, Backplane and Cabled Application**

DESCRIPTION

The SN65LVPE502 is a dual channel, single lane USB 3.0 redriver and signal conditioner supporting data rates of 5.0Gbps. The device complies with USB 3.0 spec revision 1.0, supporting electrical idle condition and low frequency periodic signals (LFPS) for USB 3.0 power management modes.

Programmable EQ, De-Emphasis and Amplitude Swing

The SN65LVPE502 is designed to minimize signal degradation effects such as crosstalk and inter-symbol interference (ISI) that limits the interconnect distance between two devices. The input stage of each channel offers selectable equalization settings that can be programmed to match loss in the channel. The differential outputs provide selectable de-emphasis to compensate for the anticipated distortion USB 3.0 signal will experience. Level of de-emphasis will depend on the length of interconnect and its characteristics. The SN65LVPE502 provides a unique way to tailor output de-emphasis on a per channel basis with use of DE and OS pins. All Rx and Tx equalization settings supported by the device are programmed by six 3-state pins as shown in Table 2.

Low Power Modes

The device supports three low power modes as described below.

1. Sleep Mode

   Initiated anytime EN_RXD undergoes a high to low transition or when device powers up with EN_RXD set low. In sleep mode both input and output terminations are held at HiZ and device ceases operation to conserve power. Sleep mode max power consumption is 1mW, entry time is 2µs, device exits sleep mode to Rx.Detect mode after EN_RXD is driven to V_{CC}, exit time is 100µs max.

2. RX Detect Mode – When no remote device is connected

   Anytime SN65LVPE502 detects a break in link (i.e., when upstream device is disconnected) or after powerup fails to find a remote device, SN65LVPE502 goes to Rx Detect mode and conserves power by shutting down majority of the internal circuitry. In this mode, input termination for both channels are driven to Hi-Z. In Rx Detect mode device power is <10mW(TYP) or less than 5% of its normal operating power This feature is useful in saving system power in mobile applications like notebook PC where battery life is critical.

Anytime an upstream device gets reconnected the redriver automatically senses the connection and goes to normal operating mode. This operation requires no setting to the device.

3. U2/U3 Mode

   With the help of internal timers the device tracks when link enters USB 3.0 low power modes U2 and U3, in these modes link is in electrical idle state. SN65LVPE502 will selectively turn-off internal circuitry to save on power. Typical power saving is about 75% lower than normal operating mode. The device will automatically revert to active mode when signaling activity (LFPS) is detected.

These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION CONTINUED

Receiver Detection

RX.Detect cycle is performed by first setting Rx termination for each channel to Hi-Z, device then starts sensing for receiver termination that may be attached at the other end of each TX.

If receiver is detected on both channel:

- The TX and RX terminations are switched to $Z_{DIFF-TX}$, $Z_{DIFF-RX}$, respectively

If no receiver is detected on one or both channels:

- The transmitter is pulled to Hi-Z
- The channel is put in low power mode
- Device attempts to detect Rx termination in 12 ms (TYP) interval until termination is found or the device is put in sleep mode.

USB Compliance Mode

The device enters USB compliance mode when both EN_RXD and CM pins are set H. This mode is used to test the transmitter for compliance to voltage and timing specifications per USB 3.0 compliance specs. In this mode each channel will maintain its low-impedance termination R_{DC-RX}, while auto Rx detect operation in the device is disabled.

Electrical Idle Support

The electrical idle support is needed for low frequency periodic signaling (LFPS) used in USB 3.0 side band communication. A link is in an electrical idle state when the TX± voltage is held at a steady constant value like the common mode voltage. SN65LVPE502 detects an electrical idle state when RX± voltage at the device pin falls below $V_{RX\_IDLE\_DIFFpp}$ min. After detection of an idle state in a given channel the device asserts electrical idle state in its corresponding TX. When RX± voltage exceeds $V_{RX\_IDLE\_DIFFpp}$ max normal operation is restored and output start passing input signal. The electrical idle exit and entry time is specified at ≤6 ns.

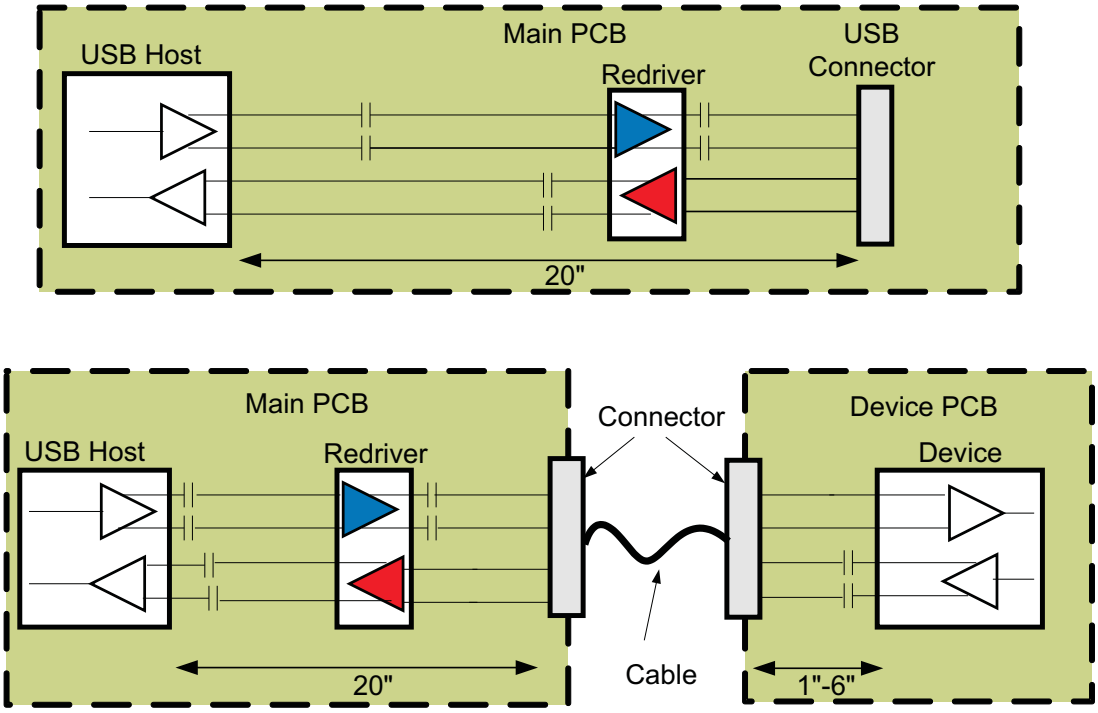


Figure 1. Typical Application

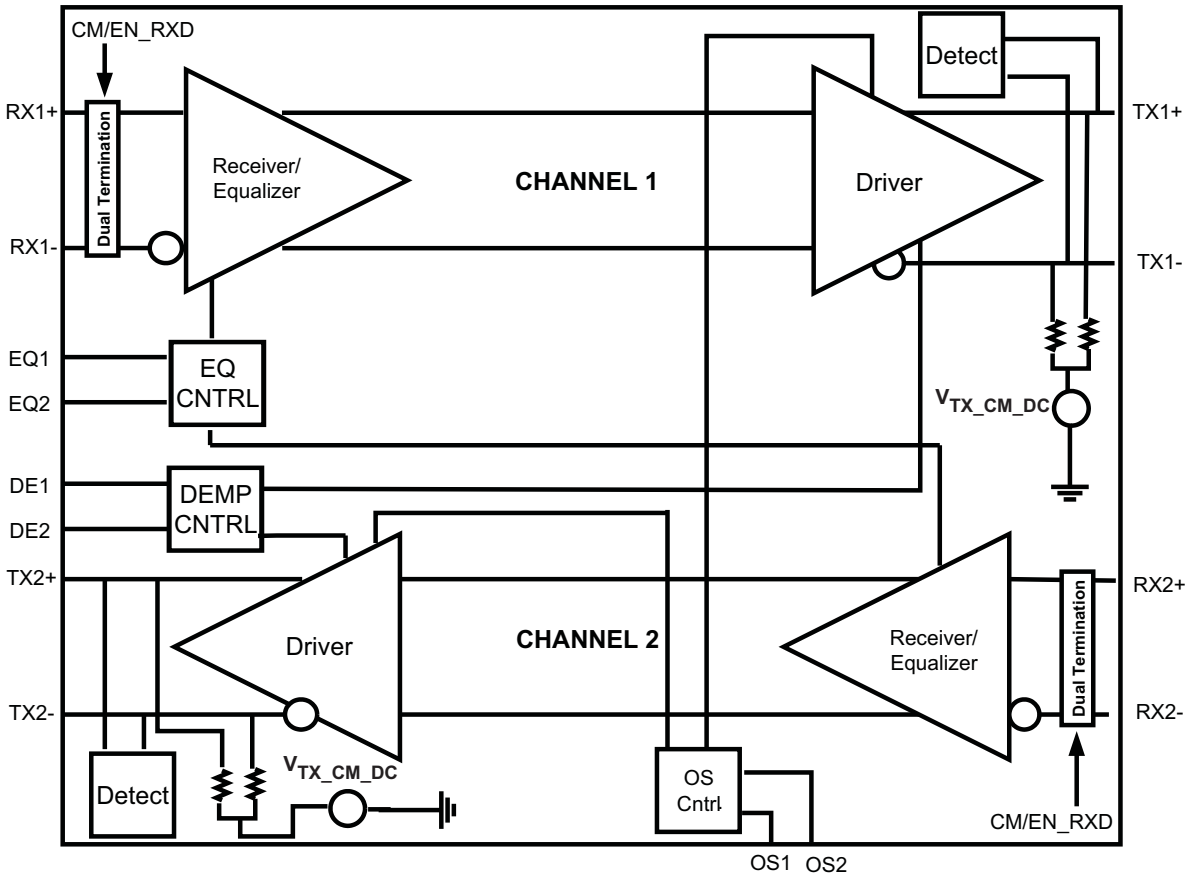


Figure 2. Data FLow Block Diagram

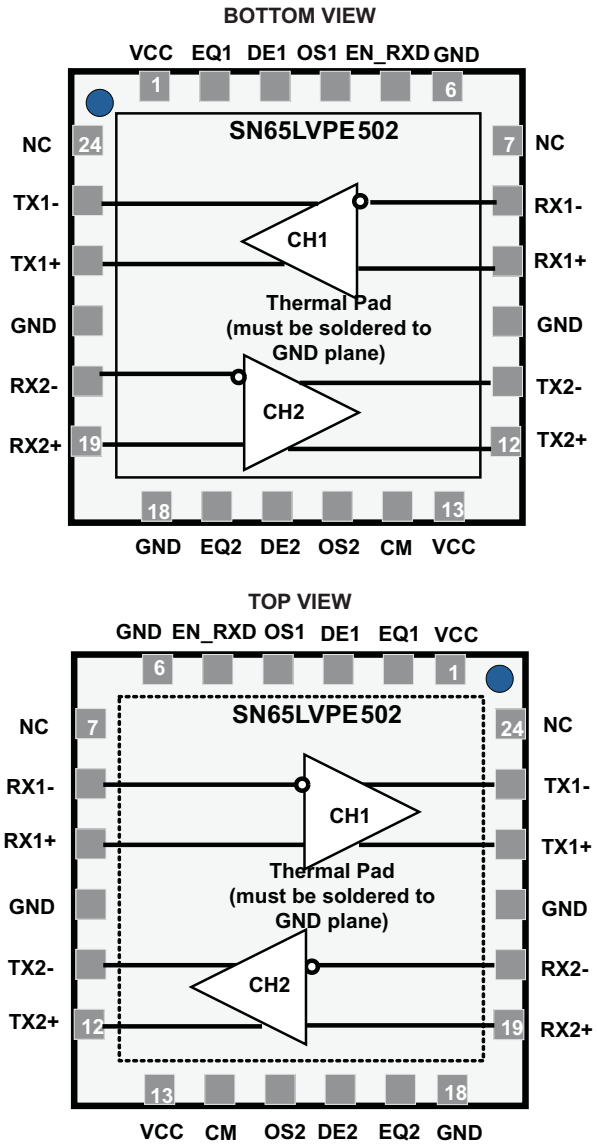


Figure 3. Flow-Through Pin-Out

Table 1. Pin Description

PIN			
NUMBER	NAME	I/O TYPE	DESCRIPTION
HIGH SPEED DIFFERENTIAL I/O PINS			
8	RX1–	I, CML	Non-inverting and inverting CML differential input for CH 1 and CH 2. These pins are tied to an internal voltage bias by dual termination resistor circuit
9	RX1+	I, CML	
20	RX2–	I, CML	
19	RX2+	I, CML	
23	TX1–	O, CML	Non-inverting and inverting CML differential output for CH 1 and CH 2. These pins are internally tied to voltage bias by termination resistors
22	TX1+	O, CML	
11	TX2–	O, CML	
12	TX2+	O, CML	

Table 1. Pin Description (continued)

PIN			
DEVICE CONTROL PIN			
5	EN_RXD	I, LVCMOS	Sets device operation modes per Table 2. Internally pulled to VCC
14	CM	I, LVCMOS	Sets device in compliance mode when pulled to VCC, internally pulled to GND
7,24	NC		Pads not internally connected
EQ CONTROL PINS(1)			
3,16	DE1, DE2	I, LVCMOS	Selects de-emphasis settings for CH 1 and CH 2 per Table 2. Internally tied to V_{CC}/2
2,17	EQ1, EQ2	I, LVCMOS	Selects equalization settings for CH 1 and CH 2 per Table 2. Internally tied to V_{CC}/2
4, 15	OS1, OS2	I, LVCMOS	Selects output amplitude for CH 1 and CH 2 per Table 2. Internally tied to V_{CC}/2
POWER PINS			
1,13	VCC	Power	Positive supply should be 3.3V ± 10%
6,10,18,21	GND	Power	Supply ground

(1) Internally biased to V_{CC}/2 with >200kΩ pull-up/pull-down. When pins are left as NC board leakage at this pin pad must be < 1 µA otherwise drive to V_{CC}/2 to assert mid-level state.

Table 2. Signal Control Pin Setting

OSx(1)	*TRANSITION* BIT AMPLITUDE (TYP mVpp)
NC (default)	1000
0	870
1	1085

EQx(1)	EQUALIZATION dB
NC (default)	0
0	7
1	15

DEx(1)	OSx(1) = NC	OSx(1) = 0	OSx(1) = 1
NC	–3.5 dB	–2.2 dB	–4.4 dB
0	–6.0 dB	–5.2 dB	–6.0 dB
1	–8.5 dB	–8.9 dB	–7.6 dB

EN_RXD	DEVICE FUNCTION
1 (default)	Normal operating mode
0	Sleep mode

CM	DEVICE FUNCTION
0 (default)	Normal Mode
1	Compliance mode

(1) Applies to Channel 1 and Channel 2 at 2.5 GHz.

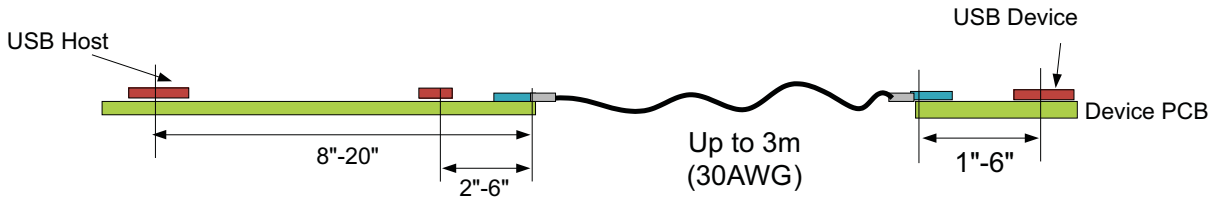


Figure 4. Redriver Placement Example

ORDERING INFORMATION(1)

PART NUMBER	PART MARKING	PCAKAGE
SN65LVPE502RGER	LVPE502	24-pin RGE Reel (large)
SN65LVPE502RGET	LVPE502	24-pin RGE Reel (small)

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)(1)

		UNITS / VALUES
Supply Voltage Range(2)	V_{CC}	–0.5 V to 4 V
Voltage Range	Differential I/O	–0.5 V to 4 V
	Control I/O	–0.5 V to V_{CC} + 0.5V
Electrostatic discharge	Human Body Model(3)	±5000V
	Charged Device Model(4)	±1500V
	Machine Model(5)	±200V
Continuous power dissipation		See Dissipation Rating Table

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
(2) All voltage values, except differential voltages, are with respect to network ground terminal.
(3) Tested in accordance with JEDEC Standard 22, Test Method A114-B.
(4) Tested in accordance with JEDEC Standard 22, Test Method C101-A.
(5) Tested in accordance with JEDEC Standard 22, Test Method A115-A.

PACKAGE CHARACTERIZATION

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
P_D	Device power dissipation	CM, EN_RXD, EQ cntrl pins = NC, K28.5 pattern at 5 Gbps, V_{ID} = 1000 mVpp		330	450	mW
P_{SD}	Device power dissipation under low power mode	EN_RXD= GND		0.3	1	mW

THERMAL INFORMATION

THERMAL METRIC(1)		SN65LVPE502 RGE 24 PINS	UNITS
θ_{JA}	Junction-to-ambient thermal resistance(2)	46	°C/W
$\theta_{JC(TOP)}$	Junction-to-case(top) thermal resistance (3)	42	
θ_{JB}	Junction-to-board thermal resistance (4)	13	
ψ_{JT}	Junction-to-top characterization parameter (5)	0.5	
ψ_{JB}	Junction-to-board characterization parameter (6)	9	
$\theta_{JC(BOTTOM)}$	Junction-to-case(bottom) thermal resistance (7)	4	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, SPRA953.
(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
(5) The junction-to-top characterization parameter, ψ_{JT}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
(6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
(7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	TYP	MAX	UNIT
V_{CC}	Supply Voltage	3	3.3	3.6	V
$C_{COUPLING}$	AC Coupling Capacitor	75		200	nF
	Operating free-air temperature	0		85	°C

DEVICE POWER

The SN65LVPE502 is designed to operate from a single 3.3 V supply.

ELECTRICAL CHARACTERISTICS

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
DEVICE PARAMETERS						
I_{CC}	Supply Current	EN_RXD, CM, EQ cntrl = NC, K28.5 pattern at 5 Gbps, V_{ID} = 1000 mV_{pp}		100	120	mA
$ICC_{Rx.Detect}$		In Rx.Detect mode		2	5	
ICC_{sleep}		EN_RXD = GND			0.1	
ICC_{U2-U3}		Link in USB low power state		21		
	Maximum Data Rate				5	Gbps
t_{ENB}	Device Enable Time	Sleep mode exit time EN_RXD L→ H With Rx termination present			100	µs
t_{DIS}	Device Disable Time	Sleep mode entry time EN_RXD H→ L			2	µs
$T_{RX.DETECT}$	Rx.Detect Start Event	Power-up time			100	µs
CONTROL LOGIC (under recommended operating conditions)						
V_{IH}	High level Input Voltage		1.4		V_{CC}	V
V_{IL}	Low Level Input Voltage		–0.3		0.5	V
V_{HYS}	Input Hysteresis			150		mV
I_{IH}	High Level Input Current	OSx, EQx, DEx = V_{CC}			30	µA
		EN_RXD = V_{CC}			1	
		CM = V_{CC}			30	
I_{IL}	Low Level Input Current	OSx, EQx, DEx = GND	–30			µA
		EN_RXD = GND	–30			
		CM = GND	–1			
RECEIVER AC/DC						
Vin_{diff_pp}	RX1, RX2 Input Voltage Swing	AC coupled differential RX peak to peak signal	100		1200	mVpp
V_{CM_RX}	RX1, RX2 Common Mode Voltage			3.3		V
Vin_{COM_P}	RX1, RX2 AC Peak common mode voltage	Measured at Rx pins with termination enabled			150	mVP
Z_{DC_RX}	DC common mode impedance		18	26	30	Ω
Z_{diff_RX}	DC differential input impedance		72	80	120	Ω
$Z_{RX\_High\_IMP+}$	DC Input High Impedance	Device in sleep mode Rx termination not powered. Measured with respect to GND over 500mV max	50	85		kΩ
$V_{RX\text{-}LFPS\text{-}DETpp}$	Low Voltage Periodic Signaling (LFPS) Detect Threshold	Measured at receiver pin, below minimum output is squelched, above max input signal is passed to output	100		300	mVpp
$RL_{RX\text{-}DIFF}$	Differential Return Loss	50 MHz – 1.25 GHz	10	11		dB
		1.25 GHz – 2.5 GHz	6	7		
$RL_{RX\text{-}CM}$	Common Mode Return Loss	50 MHz – 2.5 GHz	11	13		dB

ELECTRICAL CHARACTERISTICS (continued)

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
TRANSMITTER AC/DC						
$V_{TXDIFF\_TB\_PP}$	Differential peak-to-peak Output Voltage (VID = 800, 1200 mVpp, 5Gbps)	R_L =100Ω +1%, DEx, OSx = NC, **Transition Bit**	800	1000	1200	mV
		R_L =100Ω +1%, DEx, OSx = GND **Transition Bit**		870		
		R_L =100Ω +1%, DEx, OSx = VCC **Transition Bit**		1085		
$V_{TXDIFF\_NTB\_PP}$		R_L =100Ω +1%, DEx=NC, OSx = 0,1,NC **Non-Transition Bit**		665		
		R_L =100Ω +1%, DEx=0, OSx = 0,1,NC **Non-Transition Bit**		510		
		R_L =100Ω +1%, DEx=1 OSx = 0,1,NC **Non-Transition Bit**		375		
	De-Emphasis Level	OS1,2 = NC (for OS1,2 = 1 and 0 see Table 2)	–3.0	–3.5	–4.0	dB
				–6.0		
				–8.5		
T_{DE}	De-Emphasis Width			0.85		UI
Z_{diff_TX}	DC Differential Impedance		72	90	120	Ω
Z_{CM_TX}	DC Common Mode Impedance	Measured w.r.t to AC ground over 0-500mV	18	23	30	Ω
RL_{diff_TX}	Differential Return Loss	f = 50 MHz – 1.25 GHz	9	10		dB
		f = 1.25 GHz – 2.5 GHz	6	7		
RL_{CM_TX}	Common Mode Return Loss	f = 50 MHz – 2.5 GHz	11	12		dB
I_{TX_SC}	TX short circuit current	TX± shorted to GND			60	mA
$V_{TX\_CM\_DC}$	Transmitter DC common-mode voltage		2.0	2.6	3.0	V
$V_{TX\_CM\_AC\_Active}$	TX AC common mode voltage active			30	100	mVpp
$V_{TX\_idle\_diff\text{-}AC\text{-}pp}$	Electrical idle differential peak to peak output voltage	HPF to remove DC	0		10	mV
$V_{TX\_CM\_DeltaU1\text{-}U0}$	Absolute delta of DC CM voltage during active and idle states			35	200	mV
$V_{TX\_idle\_diff\text{-}DC}$	DC Electrical idle differential output voltage	Voltage must be low pass filtered to remove any AC component	0		10	mV
V_{detect}	Voltage change to allow receiver detect	Positive voltage to sense receiver termination			600	mV
t_R,t_F	Output Rise/Fall time	20%-80% of differential voltage measure 1" from the output pin	30	50		ps
t_{RF_MM}	Output Rise/Fall time mismatch				20	ps
T_{diff_LH}, T_{diff_HL}	Differential Propagation Delay	De-Emphasis = –3.5dB (CH 0 and CH 1). Propagation delay between 50% level at input and output See Figure 5		290	350	ps
$t_{idleEntry}$ $t_{idleExit}$	Idle entry and exit times	See Figure 6		4	6	ns
C_{TX}	Tx input capacitance to GND	At 2.5 GHz		1.25		pF
EQUALIZATION						
$T_{TX\text{-}EYE}$ (1)(2)	**Total Jitter (Tj) at point A**	Device setting: OS1 = L, DE1 = H, EQ1 = L		0.14	0.5	UIpp(3)
DJ_{TX} (2)	Deterministic Jitter (Dj)			0.06	0.3	
RJ_{TX} (2)(4)	Random Jitter (Rj)			0.08	0.2	
$T_{TX\text{-}EYE}$ (1) (2)	**Total Jitter (Tj) at point B**	Device setting: OS2 = H, DE2 = H, EQ2 = L		0.14	0.5	UIpp(3)
DJ_{TX} (2)	Deterministic Jitter (Dj)			0.06	0.3	
RJ_{TX} (2)(4)	Random Jitter (Rj)			0.08	0.2	

(1) Includes Rj at 10^{-12}
(2) Measured at the end of reference channel in Figure 8 with K28.5 pattern, V_{ID}=1000mVpp, 5Gbps, –3.5dB DE from source.
(3) UI = 200ps
(4) Rj calculated as 14.069 times the RMS random jitter for 10^{-12} BER

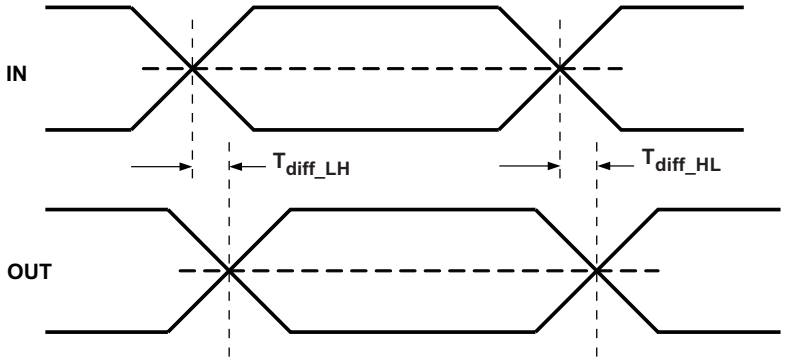


Figure 5. Propagation Delay

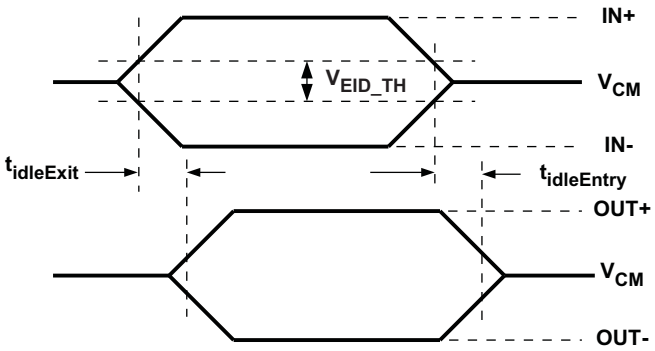


Figure 6. Electrical Idle Mode Exit and Entry Delay

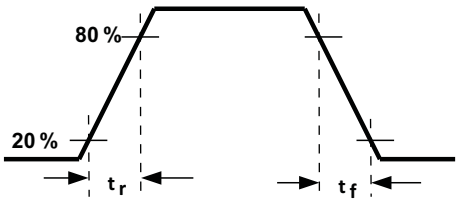
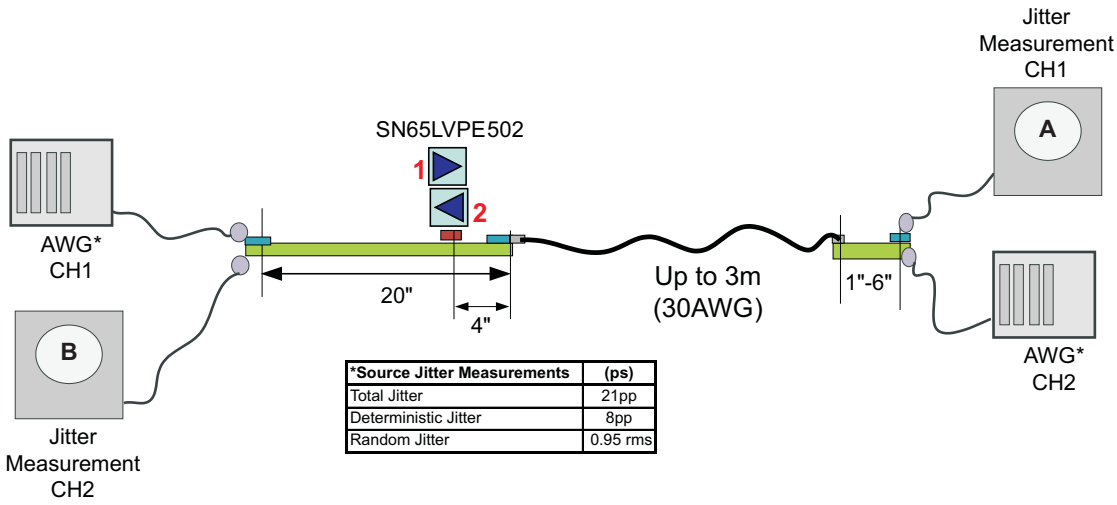


Figure 7. Output RIse and Fall Times



*Source Jitter Measurements	(ps)
Total Jitter	21pp
Deterministic Jitter	8pp
Random Jitter	0.95 rms

Figure 8. Jitter Measurement Setup

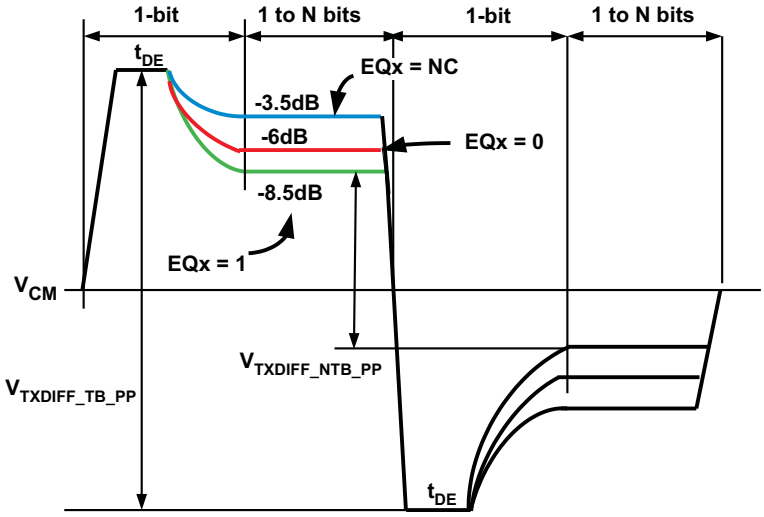


Figure 9. Output De-Emphasis Levels OSx = NC

Typical Eye Diagram and Performance Curves

Input Signal Characteristics: Data Rate = 5 Gbps, V_{ID} = 1000 mVpp, DE = -3.5 dB, Pattern = K28.5 Device Operating Conditions: VCC = 3.3 V, Temp = 25°C

Input Trace Length Held Constant and Output Cable Length Varied

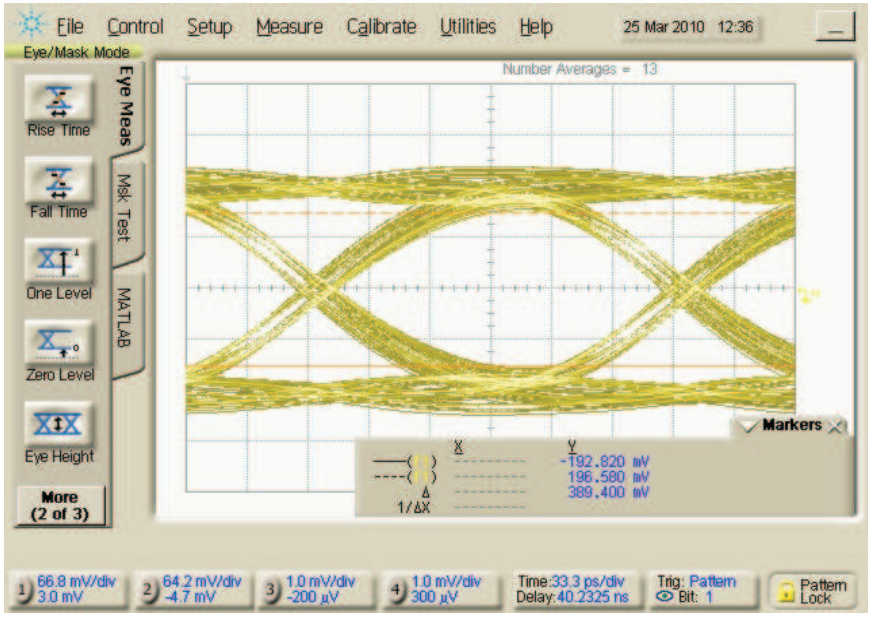


Figure 10. Input Trace = 12 Inches, 6 mil and Output USB 3 Cable Length = 1 M

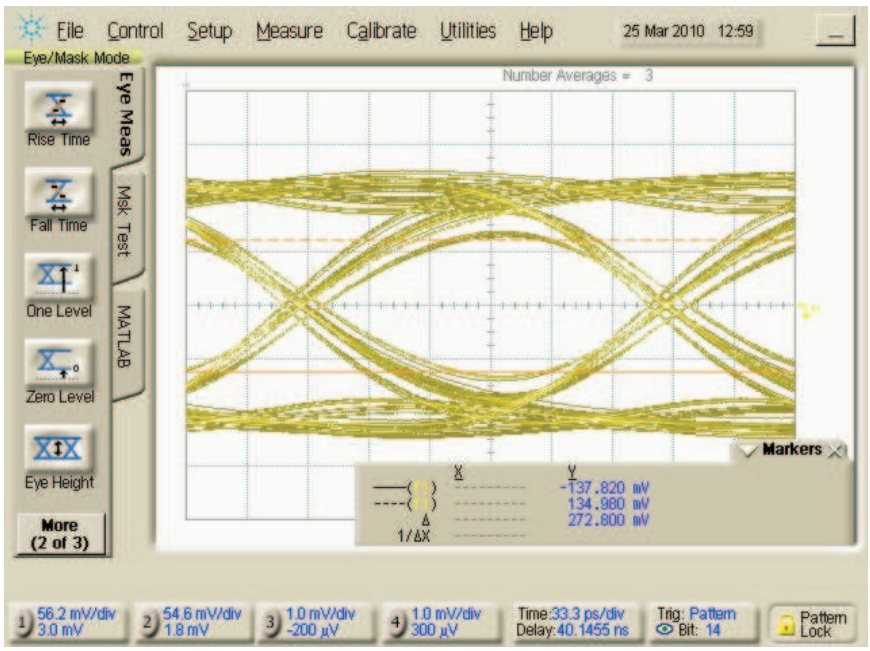


Figure 11. Input Trace = 12 Inches, 6 mil and Output USB 3 Cable Length = 2 M

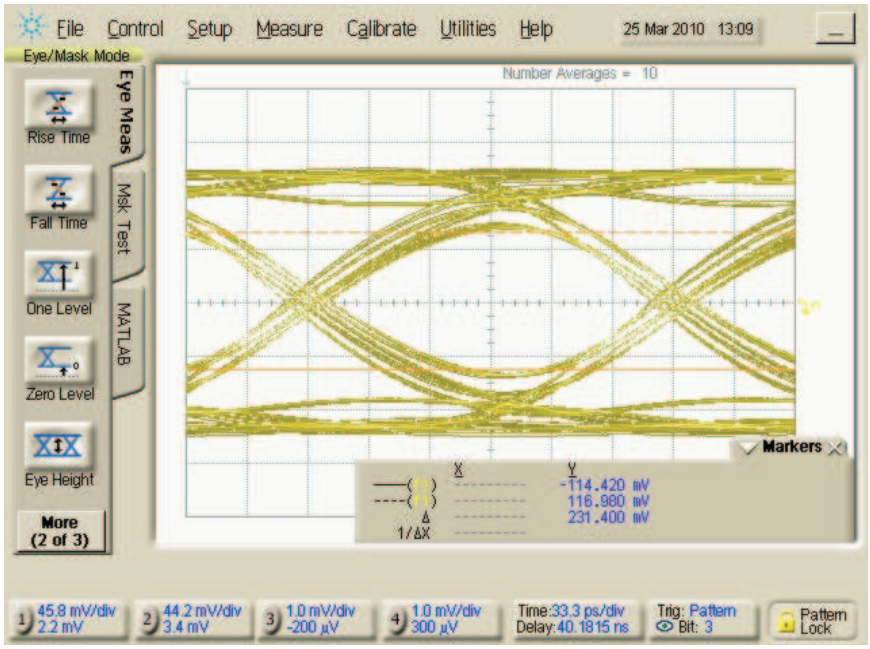


Figure 12. Input Trace = 12 Inches, 6 mil and Output USB 3 Cable Length = 3 M

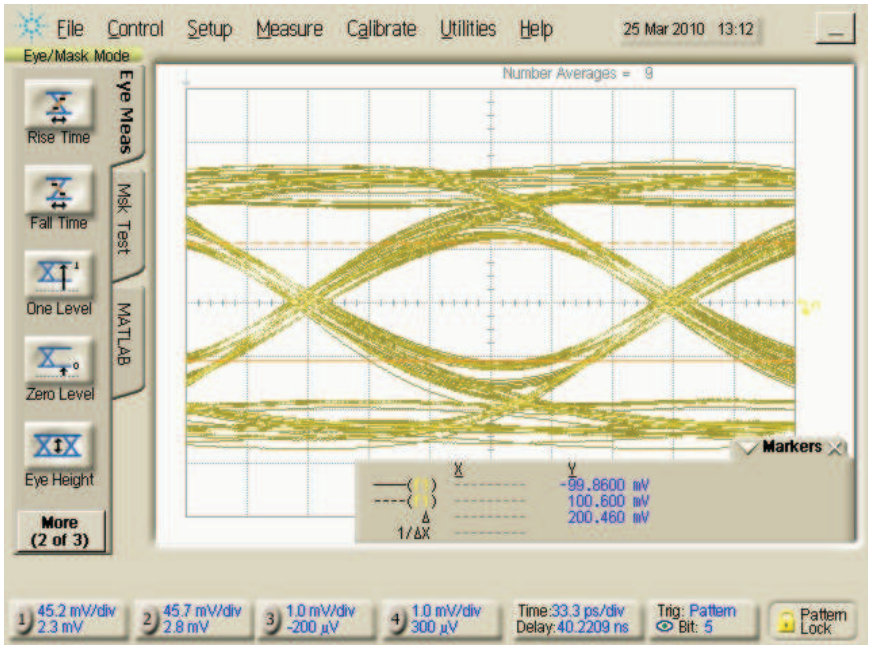


Figure 13. Input Trace = 12 Inches, 6 mil and Output USB 3 Cable Length = 4 M

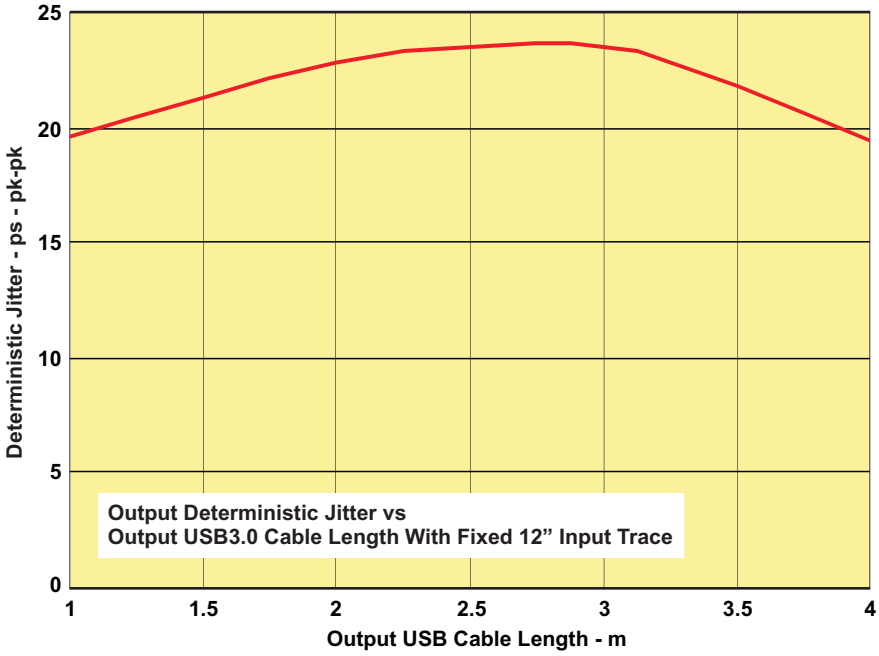


Figure 14. Jitter Performance Over Different Cable Lengths

Input Trace Length Held Constant and Output Trace Varied

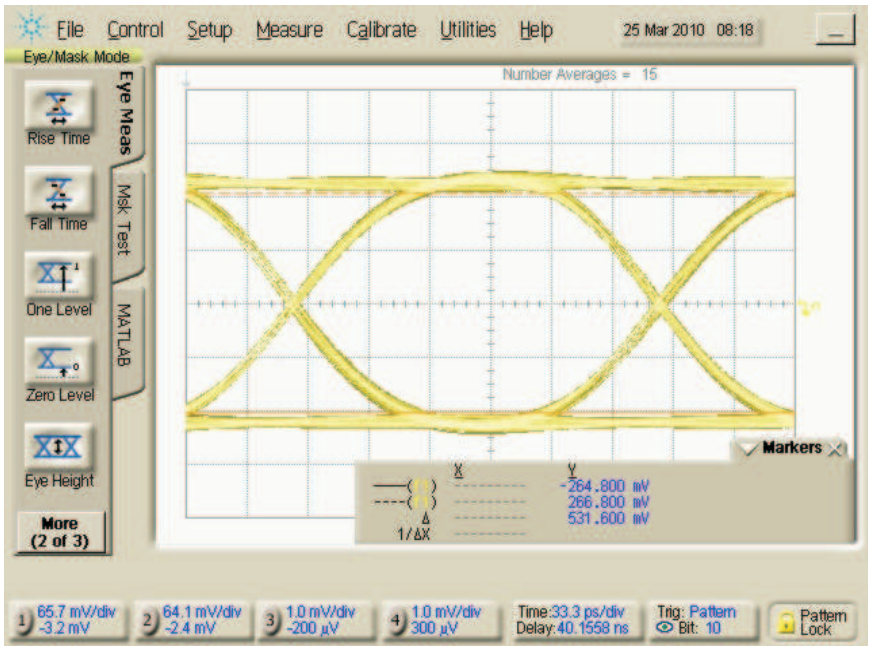


Figure 15. Input Trace = 4 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

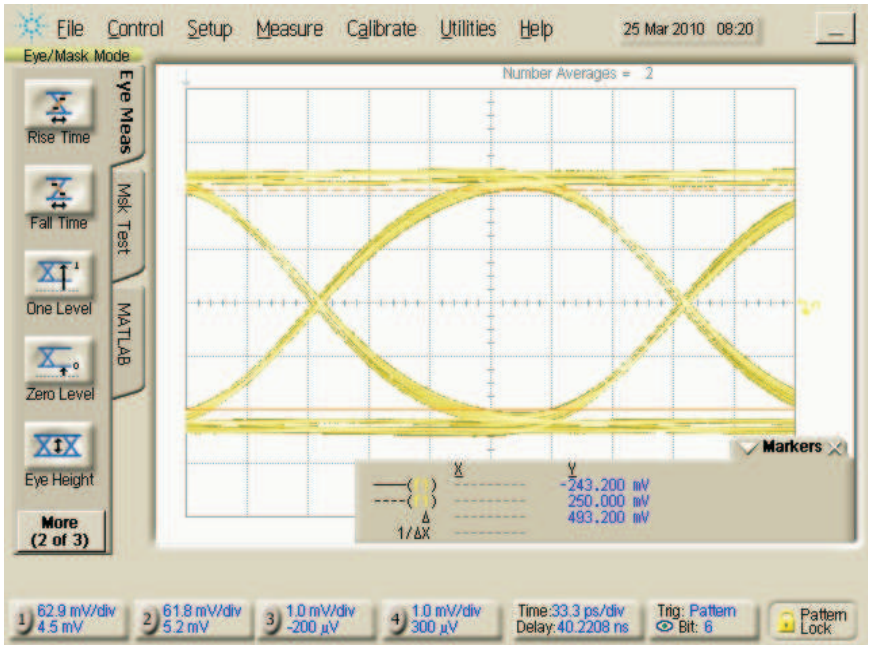


Figure 16. Input Trace = 4 Inches, 6 mil and Output Trace = 8 Inches, 6 mil

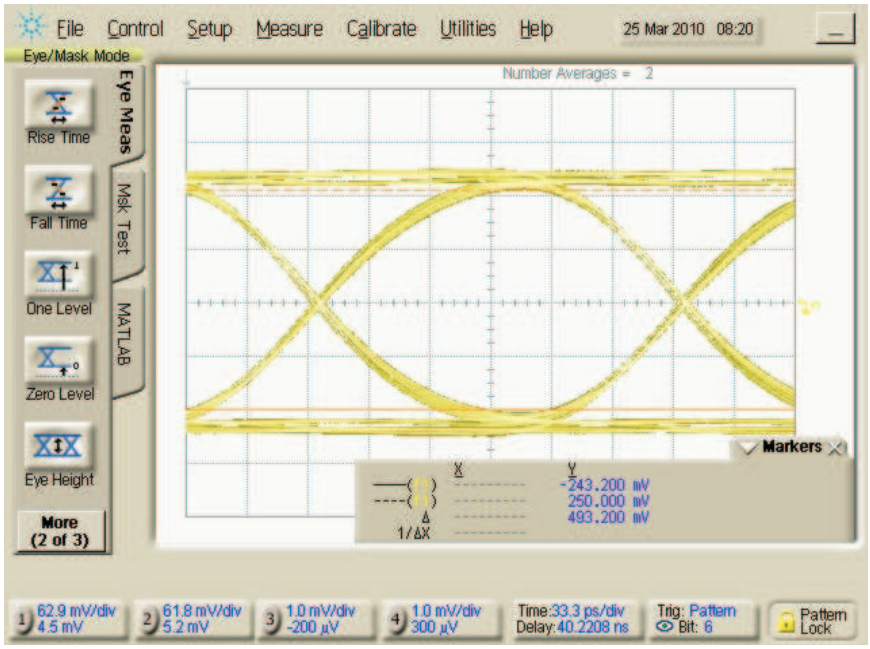


Figure 17. Input Trace = 4 Inches, 6 mil and Output Trace = 12 Inches, 6 mil

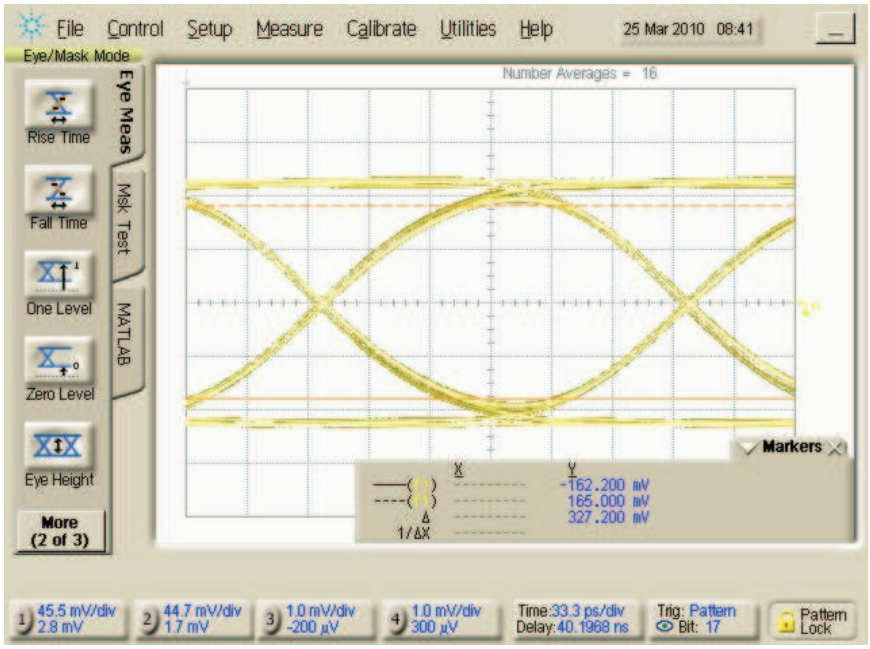


Figure 18. Input Trace = 4 Inches, 6 mil and Output Trace = 16 Inches, 6 mil

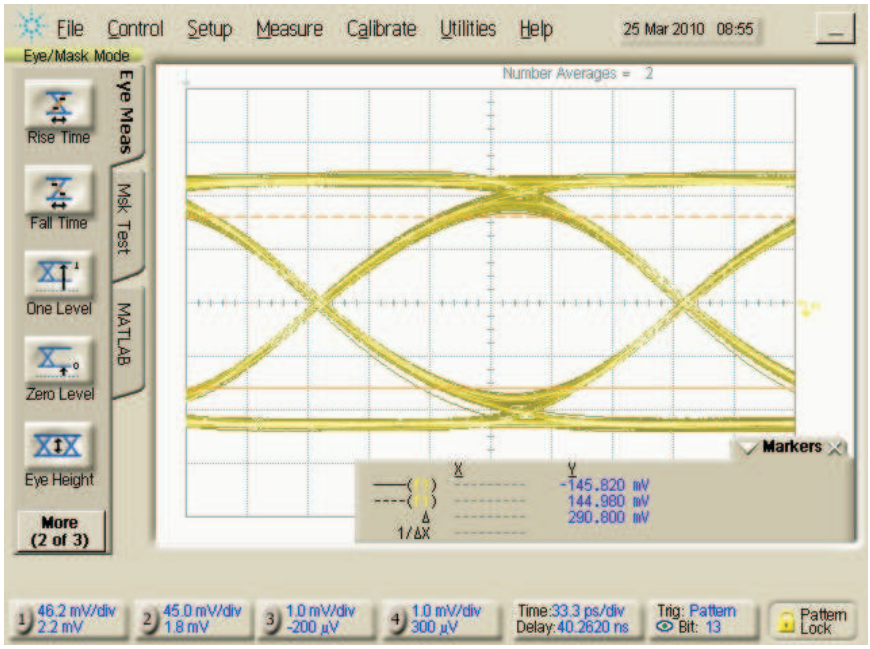


Figure 19. Input Trace = 4 Inches, 6 mil and Output Trace = 20 Inches, 6 mil

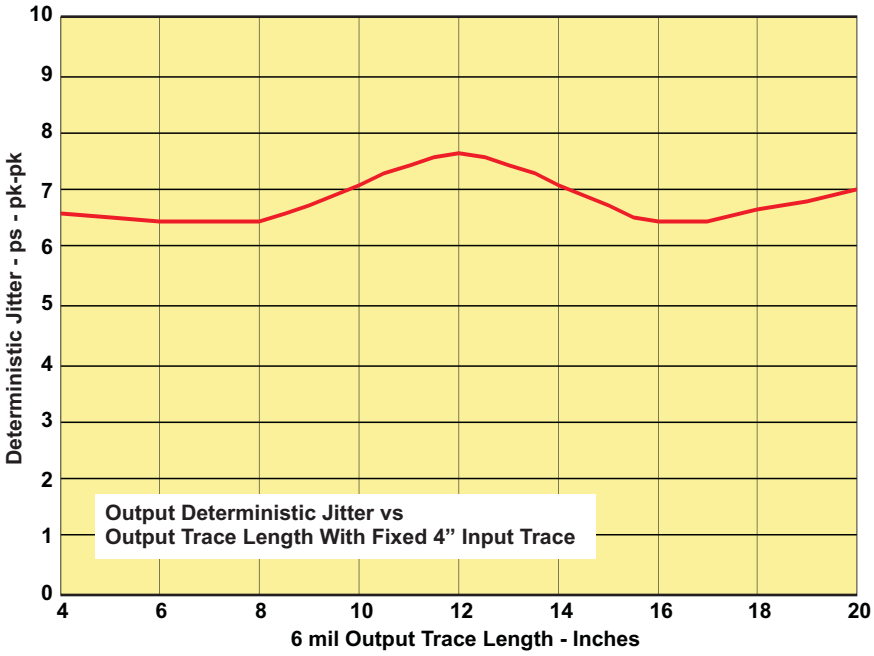


Figure 20. Jitter Performance Over Different Output Trace Lengths

Output Trace Length Held Constant and Input Trace Length Varied

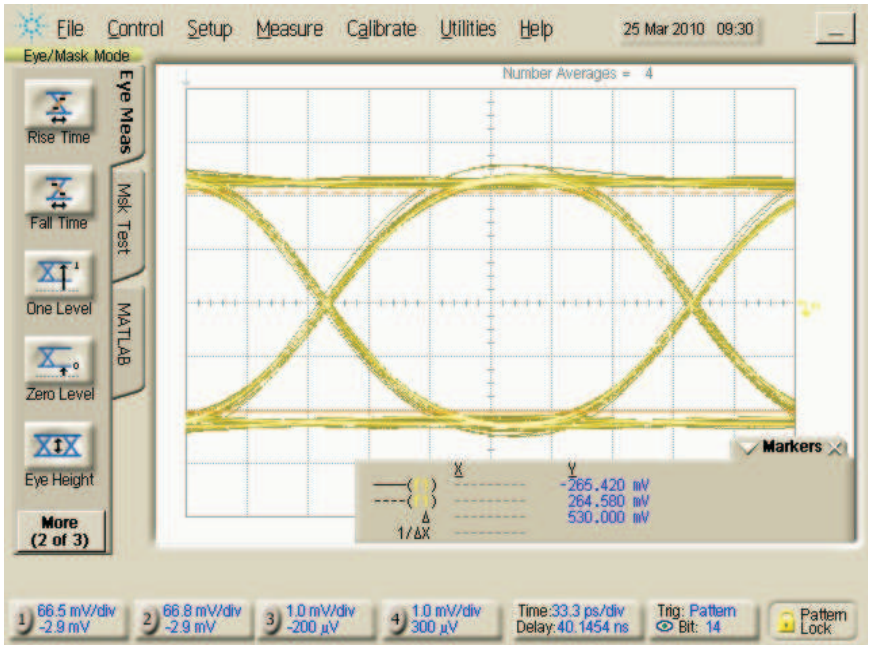


Figure 21. Input Trace = 4 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

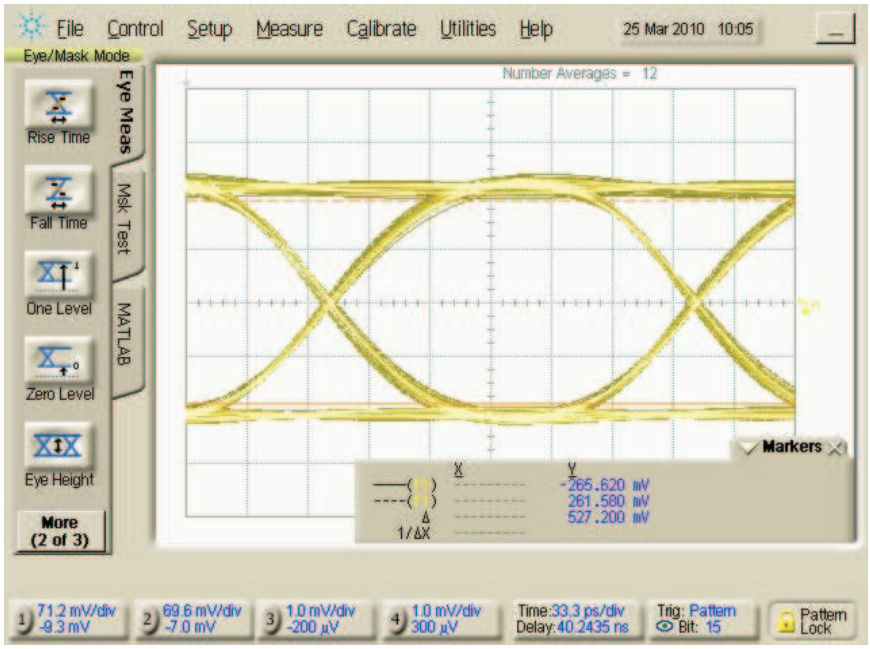


Figure 22. Input Trace = 8 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

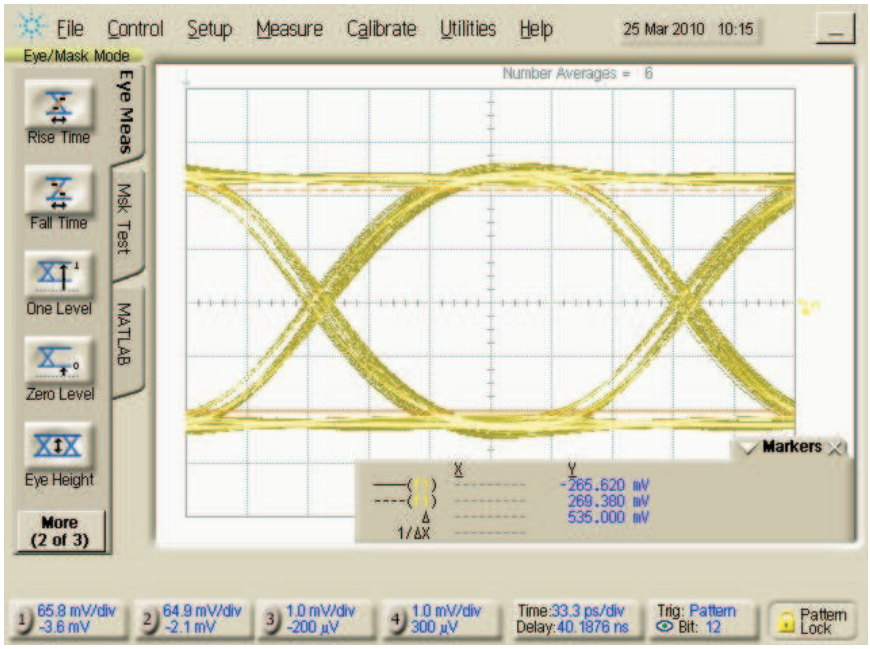


Figure 23. Input Trace = 12 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

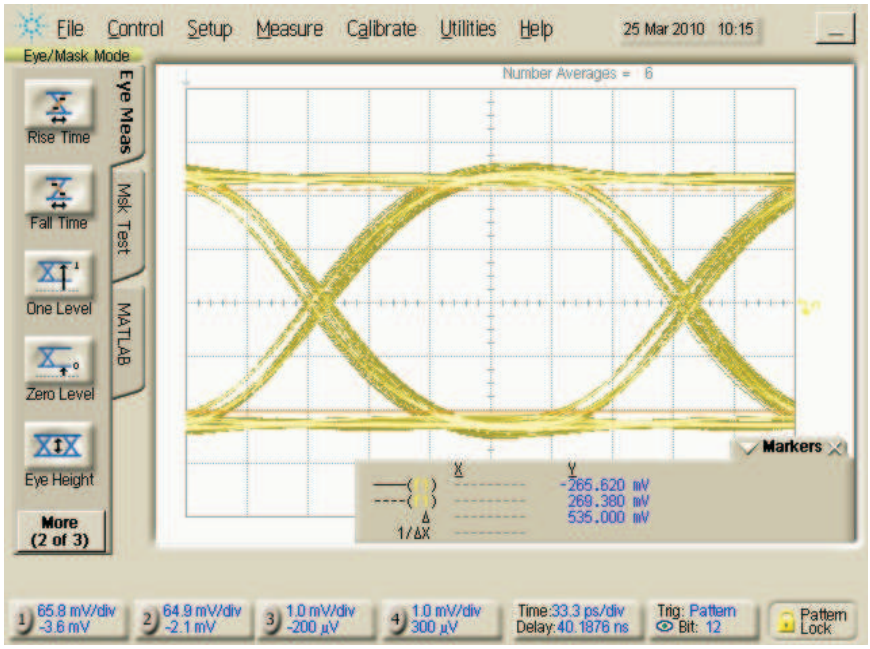


Figure 24. Input Trace = 16 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

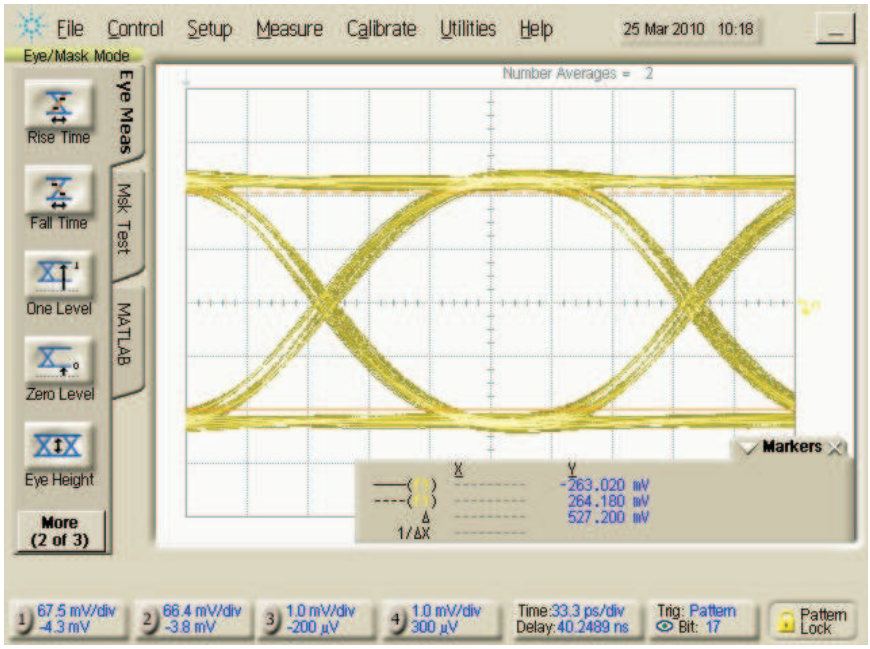


Figure 25. Input Trace = 20 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

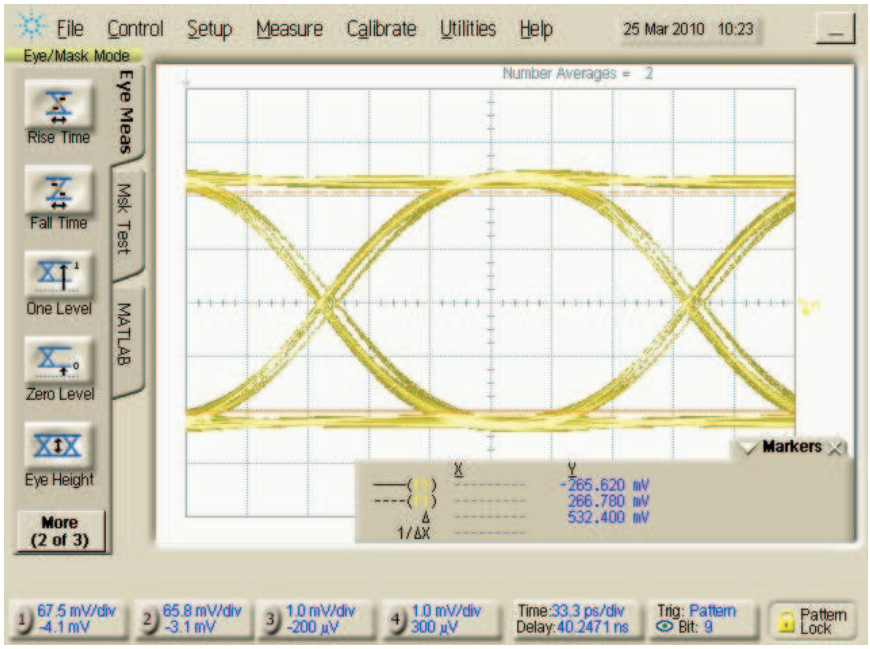


Figure 26. Input Trace = 28 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

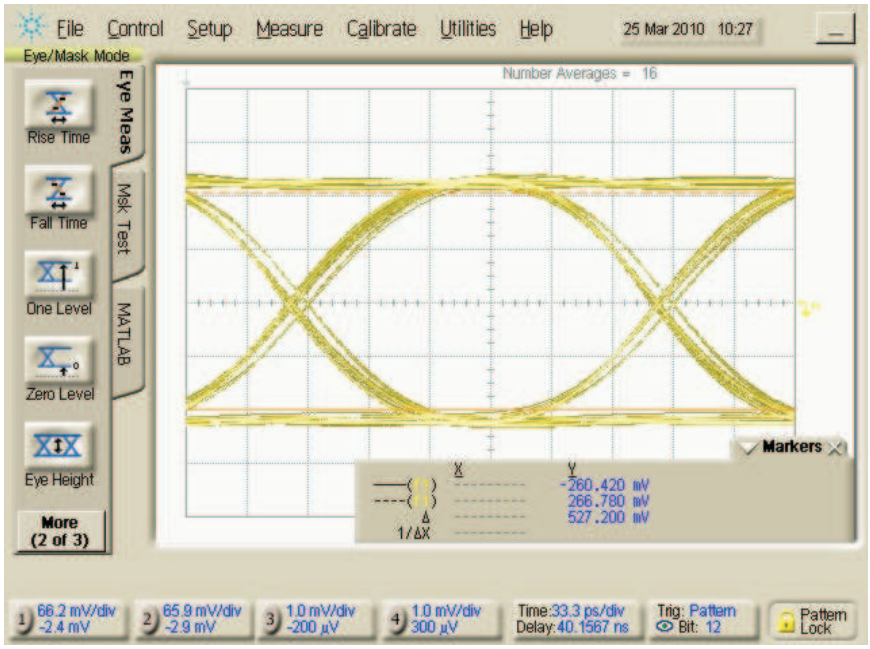


Figure 27. Input Trace = 32 Inches, 6 mil and Output Trace = 4 Inches, 6 mil

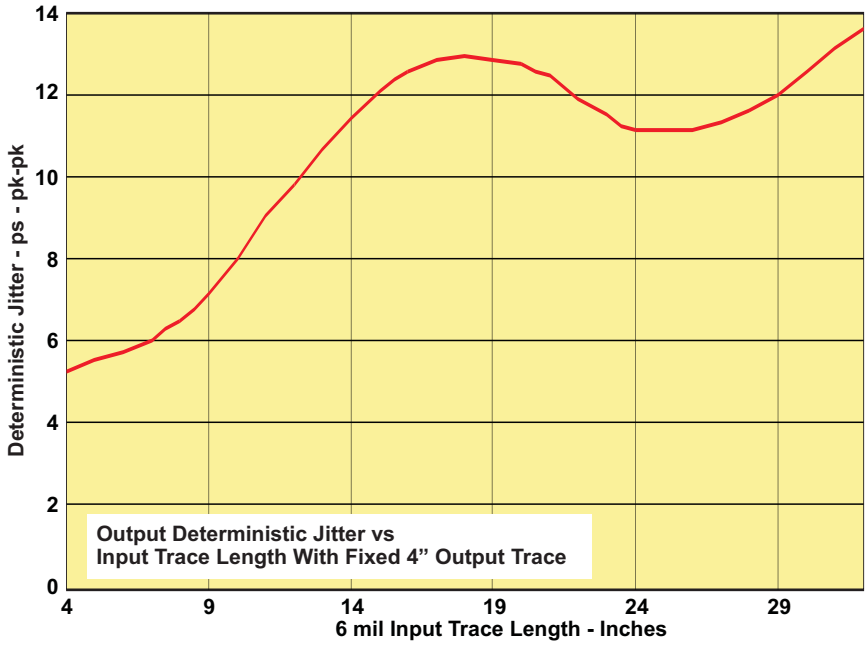


Figure 28. Jitter Performance Over Different Input Trace Lengths

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp (3)
SN65LVPE502RGER	ACTIVE	VQFN	RGE	24	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
SN65LVPE502RGET	ACTIVE	VQFN	RGE	24	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

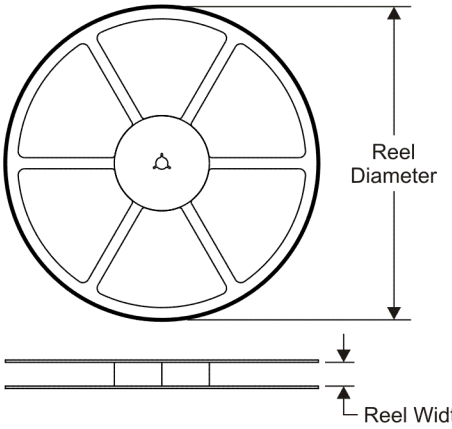
(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

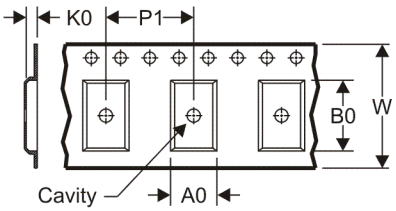
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

TAPE AND REEL INFORMATION

REEL DIMENSIONS

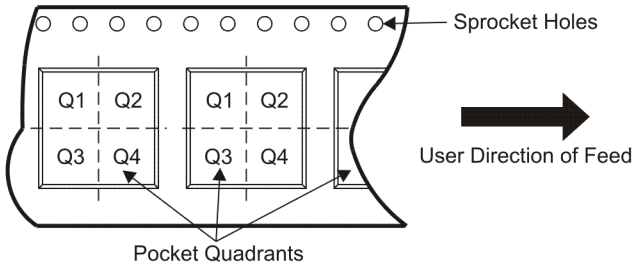


TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

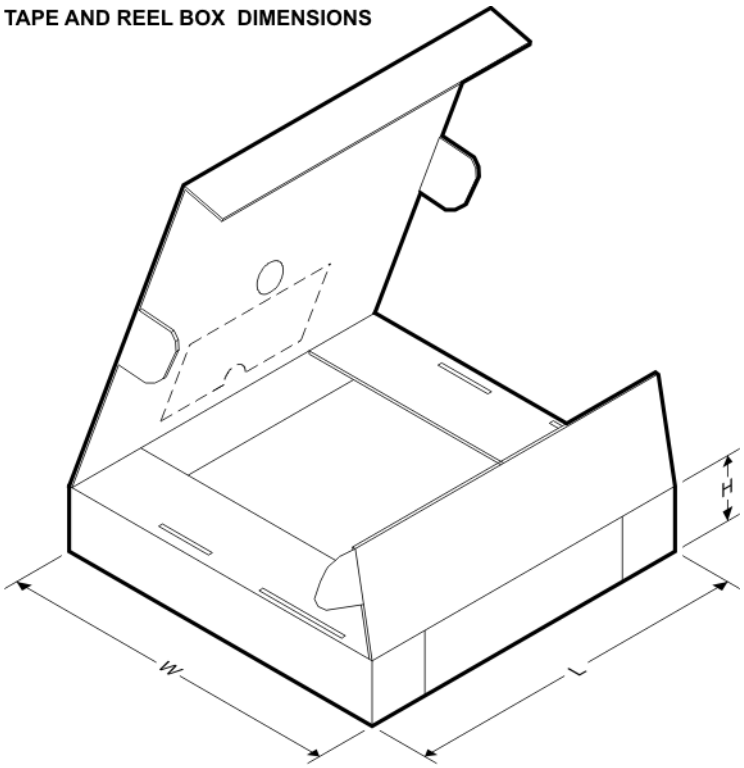
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN65LVPE502RGER	VQFN	RGE	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
SN65LVPE502RGET	VQFN	RGE	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

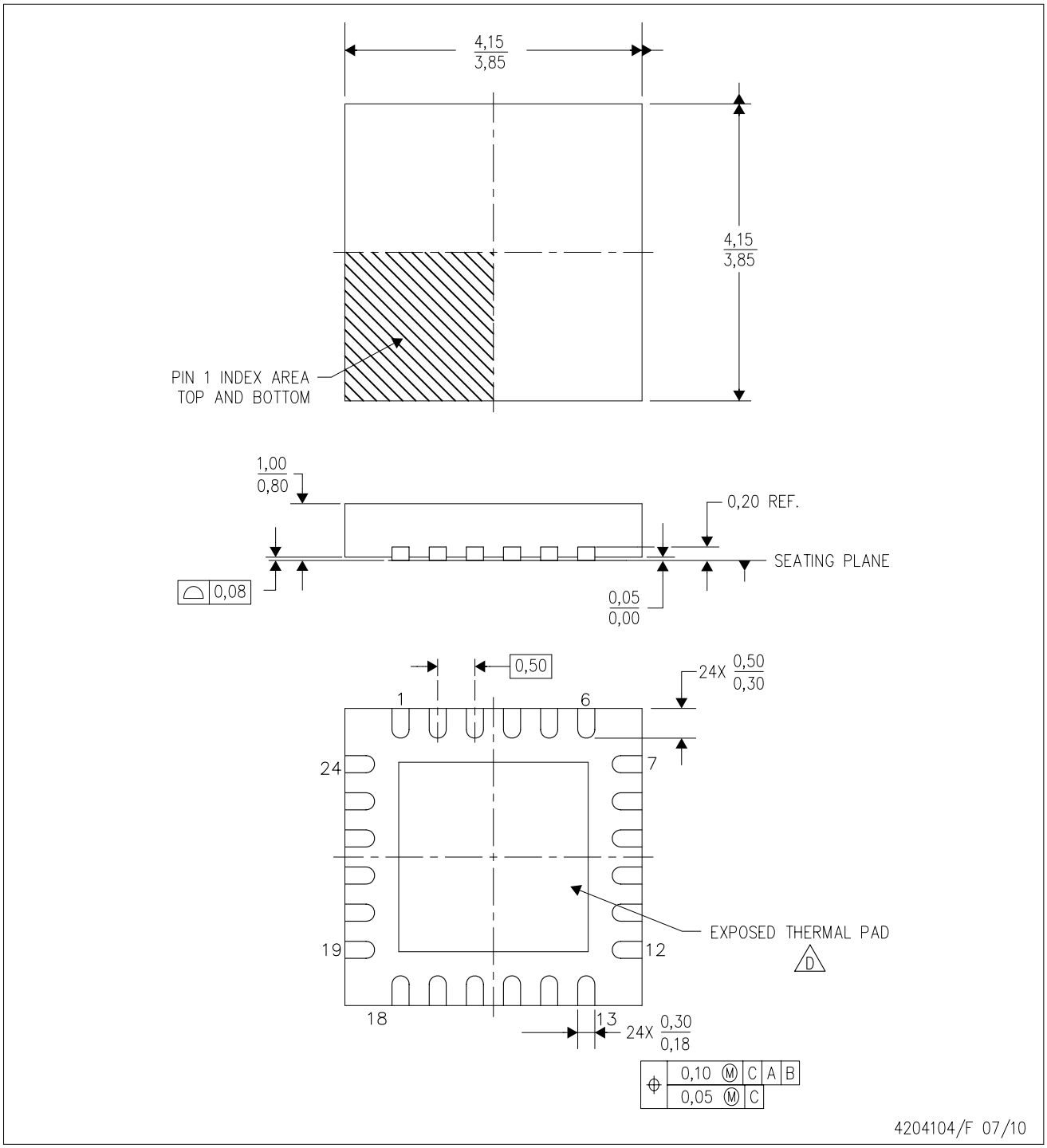
TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN65LVPE502RGER	VQFN	RGE	24	3000	346.0	346.0	29.0
SN65LVPE502RGET	VQFN	RGE	24	250	190.5	212.7	31.8

RGE (S–PVQFN–N24) PLASTIC QUAD FLATPACK NO–LEAD



NOTES:
A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M–1994.
B. This drawing is subject to change without notice.
C. Quad Flatpack, No–Leads (QFN) package configuration.
D. The package thermal pad must be soldered to the board for thermal and mechanical performance. See the Product Data Sheet for details regarding the exposed thermal pad dimensions.
E. Falls within JEDEC MO–220.

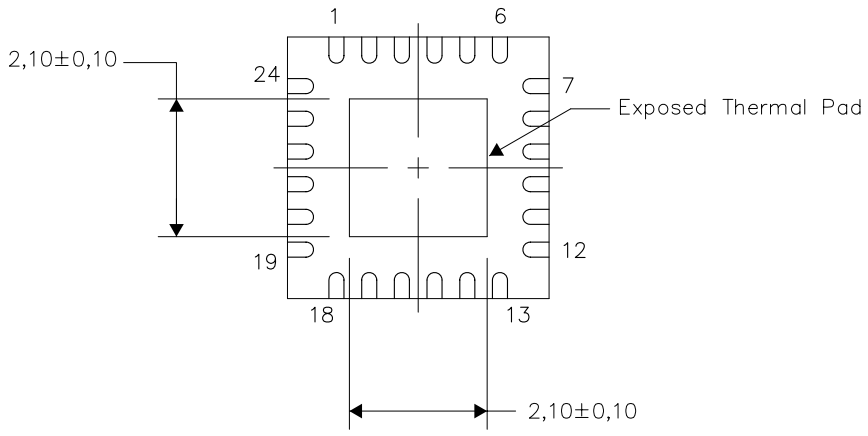
RGE (S–PVQFN–N24) PLASTIC QUAD FLATPACK NO–LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No–Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206344–6/V 11/10

NOTES: A. All linear dimensions are in millimeters

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